

## IN THE CLAIMS:

1. (Currently amended) A circuit comprising:  
a plurality of trim tracking links coupled in series;  
a plurality of detecting [[devices]] diodes wherein each detecting [[device]] diode is coupled in parallel with a corresponding trim tracking link; [[and]]  
a probe pad coupled to the string of trim tracking links; and  
a calibration diode device coupled in parallel with the plurality of trim tracking links.

2-4. (Canceled)

5. (Currently amended) The circuit of claim [[4]] 1 wherein the calibration diode device comprises at least one diode.

6. (Currently amended) The circuit of claim [[4]] 1 wherein the calibration diode device comprises a plurality of diodes coupled in series, and coupled in parallel with the plurality of trim tracking links.

7 and 8. (Canceled)

9. (Currently amended) A circuit for detecting and tracking a status of a device under laser trim comprising:

a series connected string of trim tracking links; and  
a plurality of detecting [[devices]] diodes wherein each detecting [[device]] diode is coupled in parallel with a corresponding trim tracking link; and  
a plurality of calibration diodes coupled in series, and coupled in parallel with the series connected string of trim tracking links.

10-15. (Canceled)

16. (Original) A circuit for detecting and tracking a status of a device under laser trim comprising:

at least two trim tracking links coupled in series; and

at least two trim tracking diodes wherein each trim tracking diode is coupled in parallel with a corresponding trim tracking link; and

a calibration diode device coupled in parallel with the at least two trim tracking links.

17. (Original) The circuit of claim 16 wherein the calibration diode device comprises at least one diode.

18. (Original) The circuit of claim 16 wherein the calibration diode device comprises a plurality of calibration diodes coupled in series, and coupled in parallel with the at least two trim tracking links.